

**M.Sc. 4th Semester Examination, 2010**

**PHYSICS**

**PAPER—PH-2203 (A&B)**

*Full Marks : 40*

*Time : 2 hours*

*The figures in the right-hand margin indicate marks*

*Candidates are required to give their answers in their own words as far as practicable*

*Illustrate the answers wherever necessary*

**PAPER—PH-2203 A**

**[ Marks : 20 ]**

**Answer Q.Nos.1 & 2 and any one from the rest**

**1. Answer any two bits : 2 × 2**

- (a) What is the basic requirements to obtain negative differential mobility region in the  $v_d - \epsilon$  curve of a two valley conduction band of a semiconductor ?

(Turn Over)

(b) Why CdTe shown maximum efficiency, if solar cell is made with it?

(c) Prove that in a lightly doped  $n$ -type semiconductor the conductivity minimum corresponds to

$$n = \left( \frac{\mu_p}{\mu_n} \right)^{1/2} n_i$$

where  $n_i$  is the intrinsic carrier concentration.

2. Answer any two bits :

3 × 2

(a) Prove that mobility ( $\mu$ ) in a nondegenerate semiconductor in the low temperature region is proportional to  $T^{3/2}$ .

(b) Explain how quantum well is formed by using a multilayer structure of semiconductor and describe its lasing action.

(c) Prove that Fermi level remain invariant in a  $p$ - $n$  junction under equilibrium condition.

3. (a) Find an expression of barrier potential in an abrupt  $p-n$  junction.
- (b) Derive Einstein's Relation assuming a  $p-n$  junction under equilibrium condition.
- (c) Find an expression of width of the depletion region in a metal/ $n$ -type semiconductor junction. 5 + 3 + 2
4. (a) Find an expression of growth of carrier in a semiconductor when light falls on it.
- (b) Describe the principle of Gunn effect oscillator.
- (c) What is meant by quadratic recombination? 5 + 3 + 2

PAPER—PH-2203 B

[Marks : 20]

Answer Q.No.1 and any *one* from the rest

1. Attempt any *five* : 2 × 5
- (i) What are the common method to generate X-ray?

- (ii) What is “electron gun” ?
- (iii) Give example of 0D, 1D, 2D and 3D structure.
- (iv) What is the working voltage and resolution difference between TEM and SEM ?
- (v) Match two pair :
- (i) XPS      (I) Thermal analysis
- (ii) AFM      (II) Chemical analysis
- (iii) DTA      (III) Binding energy
- (iv) LEED      (IV) Surface analysis
- (V) Surface micrograph.
- (vi) What are the basic difference between piezo and ferroelectric materials ?
- (vii) How will you distinguish the XRD spectra of amorphous and crystalline materials ?

2. (a) Discuss different section of a TEM instrument.

(b) What is photo-multiplier ?

(c) "STM is a tool to explore the atomic resolution"— Justify.

(d) What is graphene ? 4 + 2 + 3 + 1

3. (a) Write a short note on SEM.

(b) What is SOL-GEL technique ?

(c) What are the advantages of Neutron diffraction over X-ray diffraction ?

(d) Give basic idea of CVD. 4 + 2 + 2 + 2